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(54) Title: AUTONOMOUS FAULT DIAGNOSTIC TOOLS FOR MANUFACTURING SYSTEMS BY ANALYZING PROCESS RUNS

(57) Abstract: A method includes obtaining an event sequence related to a set of runs performed by a process tool that has failed, determining, using the event sequence, an issue causing a failure of the process tool, identifying, based on the issue, a first subset of runs from the set of runs and a second subset of runs from the set of runs, identifying a corrective action to address the issue that caused the failure, and causing the corrective action to be provided.

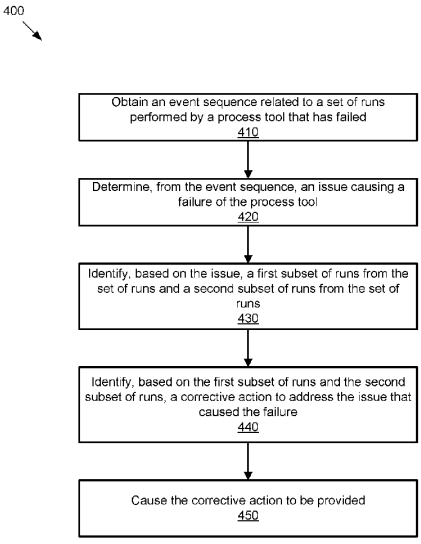

FIG. 4A

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